



GANB8R0-040CBA

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

31 January 2025

Product data sheet

1. General description

The GANB8R0-040CBA is a 40 V, 8.0 m Ω bi-directional Gallium Nitride (GaN) High Electron-Mobility-Transistor (HEMT) in a Wafer Level Chip-Scale (WLCSP) package. It is a normally-off e-mode device offering superior performance.

2. Features and benefits

- Enhancement mode - normally-off power switch
- Bi-directional device
- Ultra high switching speed capability
- Ultra-low on-state resistance
- RoHS, Pb-free, REACH-compliant
- High efficiency and high power density
- Wafer Level Chip-Scale Package (WLCSP) 1.7 mm x 1.7 mm

3. Applications

- High-side load switch
- OVP protection in smart phone USB port
- DC-to-DC converters
- Power switch circuits
- Stand-by power system

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V _{DD}	drain-drain voltage	-40 °C $\leq$ T _j $\leq$ 125 °C	[1]	-	-	40	V
I _D	drain current	V _{GD} = 5 V; T _{mb} = 25 °C	[2] [3]	-	-	14	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; Fig. 1		-	-	15	W
T _j	junction temperature			-40	-	125	°C
Static characteristics							
R _{DDon}	drain-drain on-state resistance	V _{GD2} = 5 V; I _{D1} = 10 A; T _j = 25 °C; Fig. 9; Fig. 10; Fig. 11	[1]	-	6.1	8	m Ω
		V _{GD2} = 5 V; I _{D1} = 10 A; T _j = 125 °C; Fig. 9; Fig. 12	[1]	-	11	-	m Ω

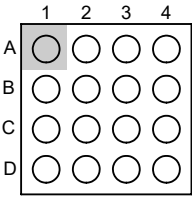
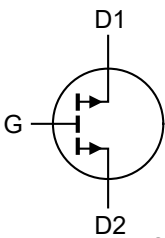
40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Dynamic characteristics							
$Q_{G(tot)}$	total gate charge	$I_D = 10\text{ A}$; $V_{DS} = 20\text{ V}$; $V_{GS} = 5\text{ V}$; $T_j = 25\text{ °C}$; Fig. 13 ; Fig. 14	[2]	-	10.1	-	nC

- [1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.
- [2] D1 and D2 are symetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.
- [3] Limited by solder ball.

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
B2-B4, D1-D4	D1	drain1	 Transparent top view WLCSP16_SOT8087	 <i>aaa-037587</i>
A1-A4, C2-C4	D2	drain2		
B1, C1	G	gate		

6. Ordering information

Table 3. Ordering information

Type number	Orderable part number, (Ordering code (12NC))	Package		
		Name	Description	Version
GANB8R0-040CBA	GANB8R0-040CBAZ (934667631341)	WLCSP16	WLCSP16, 1.7 mm x 1.7 mm	WLCSP16_SOT8087

7. Marking

Table 4. Marking codes

Type number	Marking code
GANB8R0-040CBA	8R0ACBA

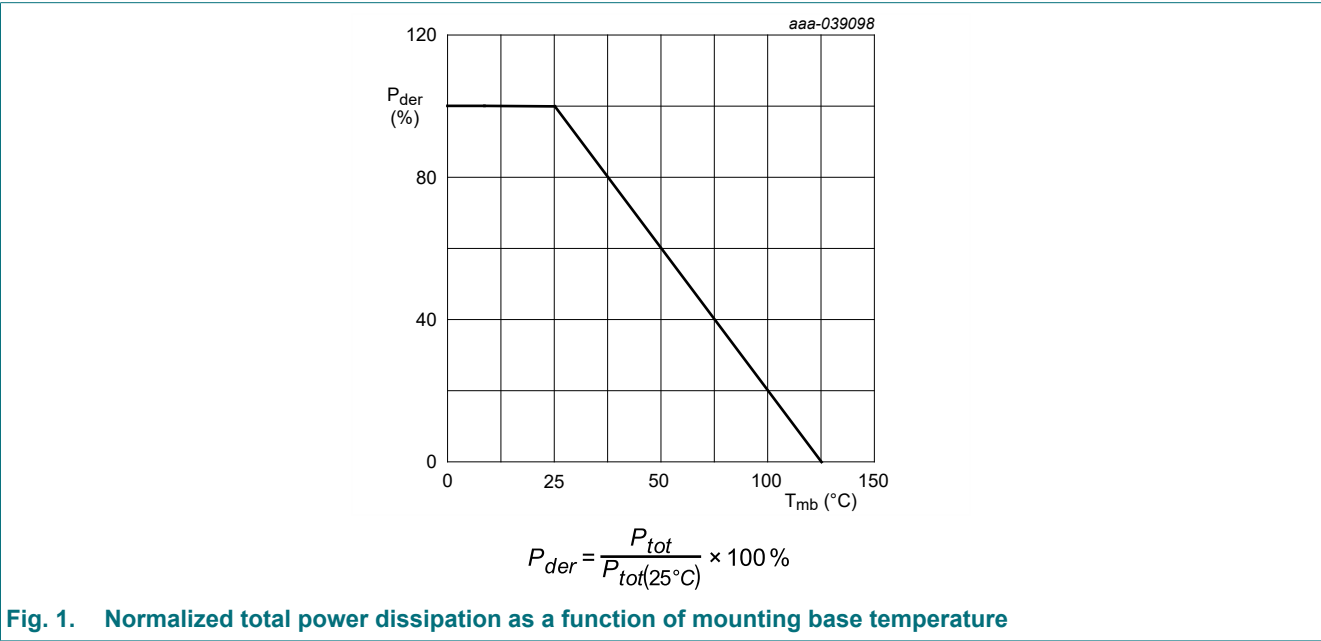
40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

8. Limiting values

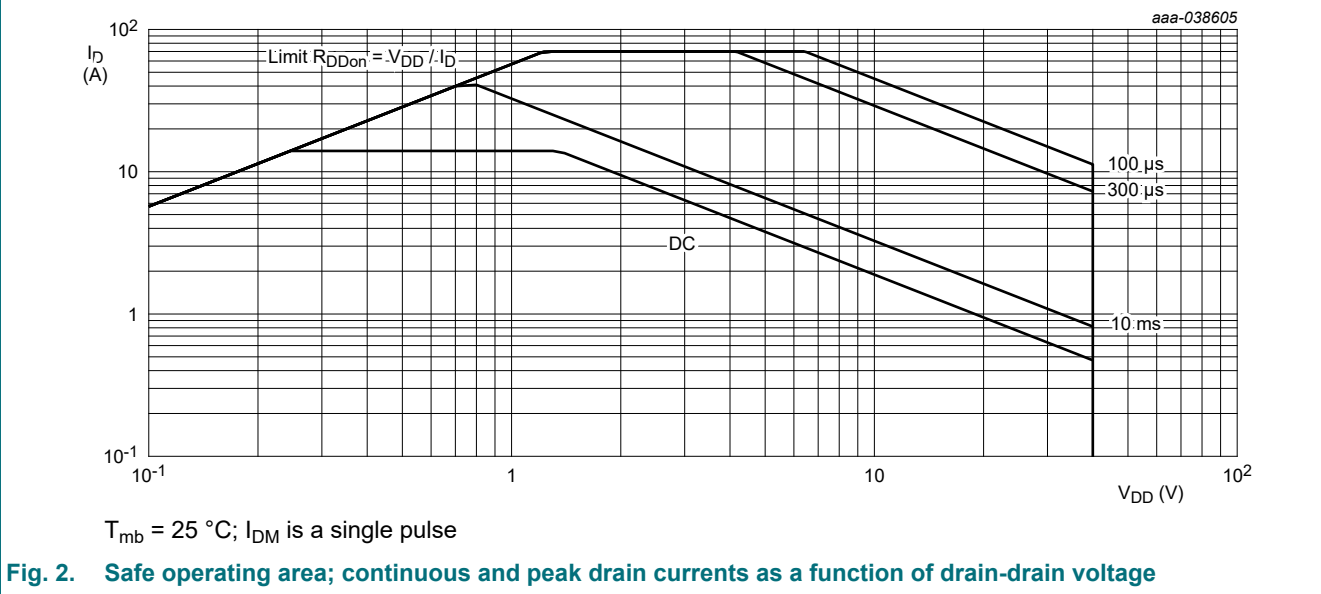
Table 5. Limiting values
In accordance with the Absolute Maximum Rating System (IEC 60134). $T_j = 25\text{ }^{\circ}\text{C}$ unless otherwise stated.

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DD}	drain-drain voltage	$-40\text{ }^{\circ}\text{C} \leq T_j \leq 125\text{ }^{\circ}\text{C}$	[1]	-	40	V
V_{DG}	drain-gate voltage		[1]	-	40	V
V_{GD}	gate-drain voltage		[1]	-	6	V
I_D	drain current	$V_{GD} = 5\text{ V}; T_{mb} = 25\text{ }^{\circ}\text{C}$	[2] [3]	-	14	A
I_{DM}	peak drain current	pulsed; $t_p \leq 300\text{ }\mu\text{s}; T_{mb} = 25\text{ }^{\circ}\text{C}$; Fig. 2	[2] [3]	-	70	A
P_{tot}	total power dissipation	$T_{mb} = 25\text{ }^{\circ}\text{C}$; Fig. 1		-	15	W
T_{stg}	storage temperature			-40	150	$^{\circ}\text{C}$
T_j	junction temperature			-40	125	$^{\circ}\text{C}$
$T_{sld(M)}$	peak soldering temperature			-	260	$^{\circ}\text{C}$

- [1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.
- [2] D1 and D2 are symetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.
- [3] Limited by solder ball.



40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

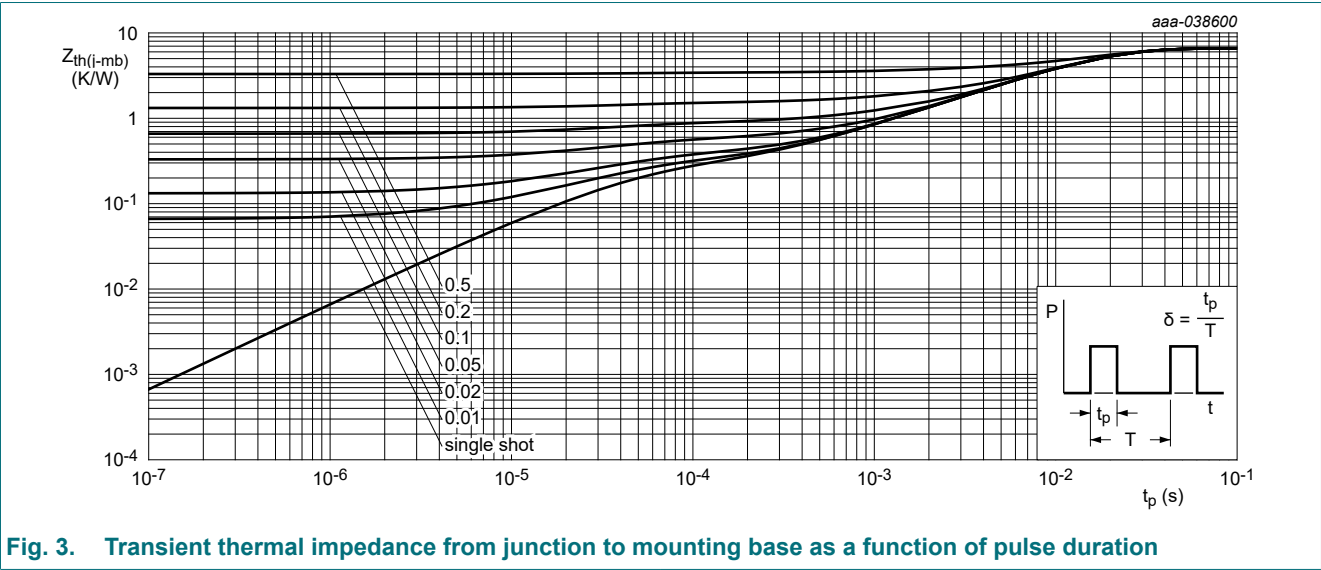


9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-c)}$	thermal resistance from junction to case		[1]	-	-	0.97	K/W
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 3		-	-	6.61	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		[2]	-	-	65.12	K/W

- [1] Thermal junction to top side of package.
[2] $R_{th(j-a)}$ is determined with the device mounted on one square inch of copper pad single layer 2 oz copper on FR4 board.



10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
BV_{DDs}	drain-drain breakdown voltage	$I_{D1D2} = 500 \mu A$; $V_{D2} = V_G = 0 V$; $T_j = 25^\circ C$	[1]	40	-	-	V
$V_{GD(th)}$	gate-drain threshold voltage	$I_D = 1 mA$; $V_{D1} = 0 V$; $V_{D2} = V_G$; $T_j = 25^\circ C$; Fig. 8	[1]	0.8	1.35	2.4	V
		$I_D = 1 mA$; $V_{D1} = 0 V$; $V_{D2} = V_G$; $T_j = 125^\circ C$; Fig. 8		-	1.1	-	V
I_{DDs}	drain-drain leakage current	$V_{DD} = 40 V$; $V_{GD} = 0 V$; $T_j = 25^\circ C$	[1]	-	0.1	20	μA
I_{GDS}	gate leakage current	$V_{GD} = 5 V$; $V_{DD} = 0 V$; $T_j = 25^\circ C$	[1]	-	0.5	5	μA
		$V_{GD} = -5 V$; $V_{DD} = 0 V$; $T_j = 25^\circ C$	[2]	-30	-	-	μA
		$V_{GD} = 6 V$; $V_{DD} = 0 V$; $T_j = 25^\circ C$		-	5	30	μA
		$V_{GD} = -6 V$; $V_{DD} = 0 V$; $T_j = 25^\circ C$		-40	-	-	μA
		$V_{GD} = 5 V$; $V_{DD} = 0 V$; $T_j = 85^\circ C$	[1]	-	0.5	5	μA
		$V_{GD} = -5 V$; $V_{DD} = 0 V$; $T_j = 85^\circ C$		-30	-	-	μA
		$V_{GD} = 6 V$; $V_{DD} = 0 V$; $T_j = 85^\circ C$		-	5	30	μA
		$V_{GD} = -6 V$; $V_{DD} = 0 V$; $T_j = 85^\circ C$		-40	-	-	μA
R_{DDon}	drain-drain on-state resistance	$V_{GD2} = 5 V$; $I_{D1} = 10 A$; $T_j = 25^\circ C$; Fig. 9; Fig. 10; Fig. 11	[1]	-	6.1	8	m Ω
		$V_{GD2} = 5 V$; $I_{D1} = 10 A$; $T_j = 125^\circ C$; Fig. 9; Fig. 12		-	11	-	m Ω
R_G	gate resistance	$f = 1 MHz$; $T_j = 25^\circ C$	[1]	-	3.2	-	Ω
Dynamic characteristics							
$Q_{G(tot)}$	total gate charge	$V_{DS} = 20 V$; $V_{GS} = 5 V$; $I_D = 10 A$; $T_j = 25^\circ C$; Fig. 13; Fig. 14	[3]	-	10.1	-	nC
Q_{GS}	gate-source charge			-	1.2	-	nC
Q_{GD}	gate-drain charge			-	5.5	-	nC
C_{iss}	input capacitance	$V_{DS} = 20 V$; $V_{GS} = 0 V$; $f = 1 MHz$; $T_j = 25^\circ C$; Fig. 15	[3]	-	566	-	pF
C_{oss}	output capacitance			-	243	-	pF
C_{rss}	reverse transfer capacitance			-	145	-	pF
Q_{oss}	output charge	$V_{DS} = 20 V$; $V_{GS} = 0 V$; $T_j = 25^\circ C$; Fig. 7	[3][4]	-	8	-	nC

- [1] Parameters are understood to apply for either polarity of bias. For example, V_{DD} is the same whether D1 is the source and D2 is the drain or vice versa.
- [2] Specification is validated during qualification at 25°C only
- [3] D1 and D2 are symmetrical with respect to the gate, G. Either can take the function of source or drain. For datasheet parameters, the source is defined as the terminal, D1 or D2, which has lower potential in the test circuit. The drain is the terminal with the higher potential.
- [4] Q_r is not specified separately from Q_{oss} for e-mode GaN FETs, since $Q_r = Q_{oss} + Q_D$, and $Q_D = 0$. (Q_D is charge associated with diffusion of minority carriers. Since there is no body diode, no minority carriers in excess of Q_{oss} have to be transferred for e-mode GaN FETs.)

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

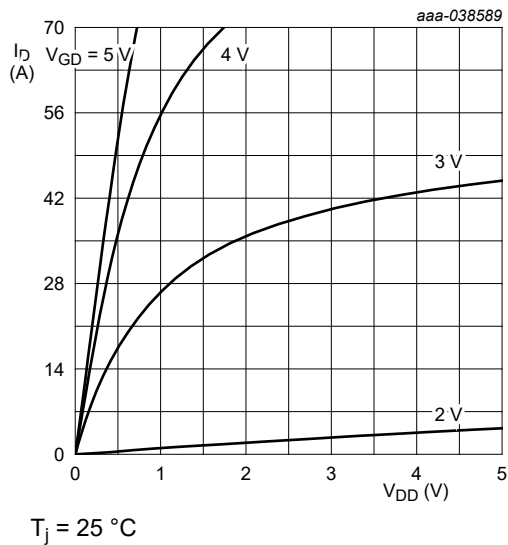


Fig. 4. Output characteristics; drain current as a function of drain-drain voltage; typical values

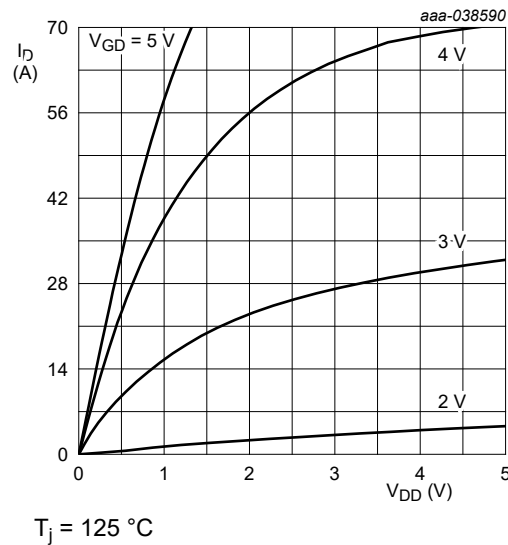


Fig. 5. Output characteristics; drain current as a function of drain-drain voltage; typical values

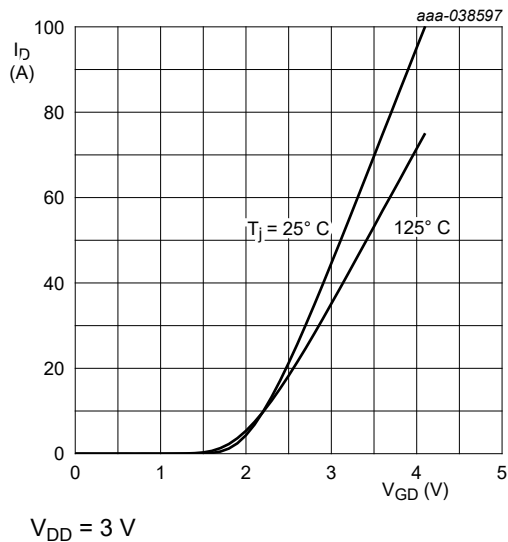


Fig. 6. Transfer characteristics; drain current as a function of gate-drain voltage; typical values

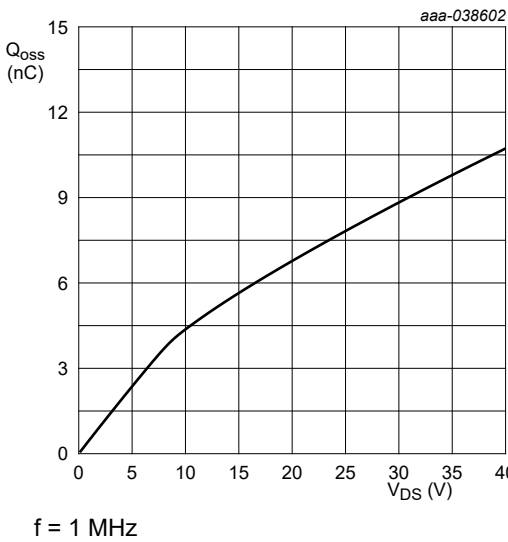
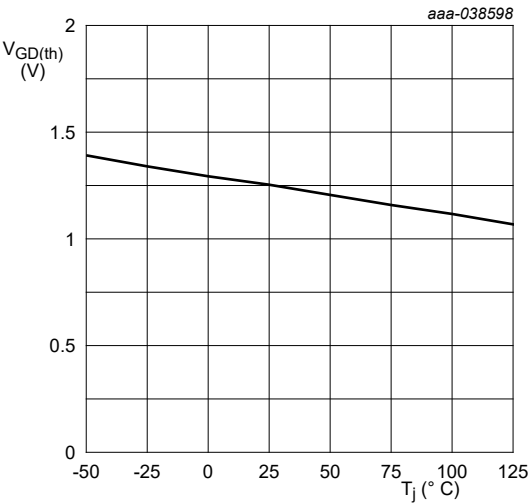


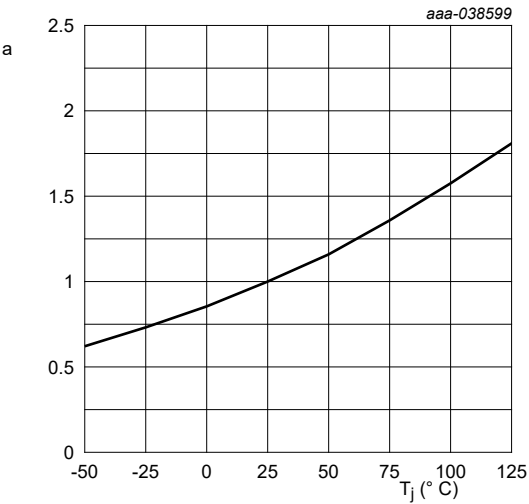
Fig. 7. Output charge as a function of drain-source voltage; typical values

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)



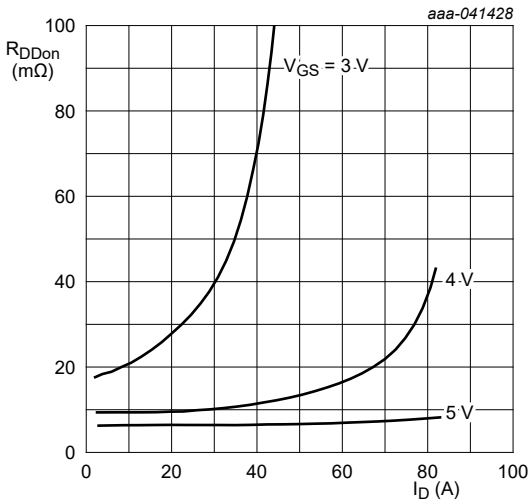
$I_D = 1 \text{ mA}$; $V_{DD} = V_{GD}$

Fig. 8. Gate-drain threshold voltage as a function of junction temperature; typical values



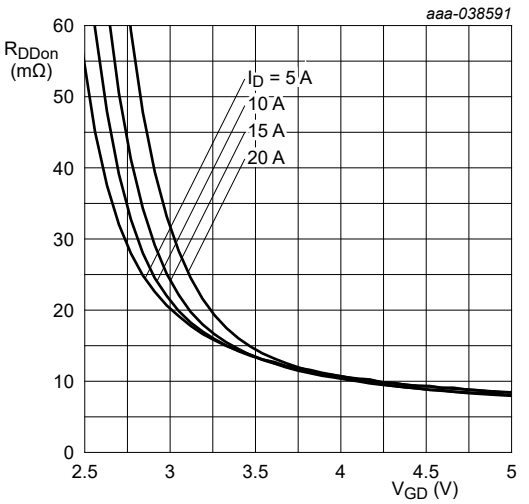
$$a = \frac{R_{DDon}}{R_{DDon}(25^\circ\text{C})}$$

Fig. 9. Normalized drain-drain on-state resistance factor as a function of junction temperature; typical values



$T_j = 25^\circ\text{C}$

Fig. 10. Drain-drain on-state resistance as a function of drain current; typical values



$T_j = 25^\circ\text{C}$

Fig. 11. Drain-drain on-state resistance as a function of gate-drain voltage; typical values

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

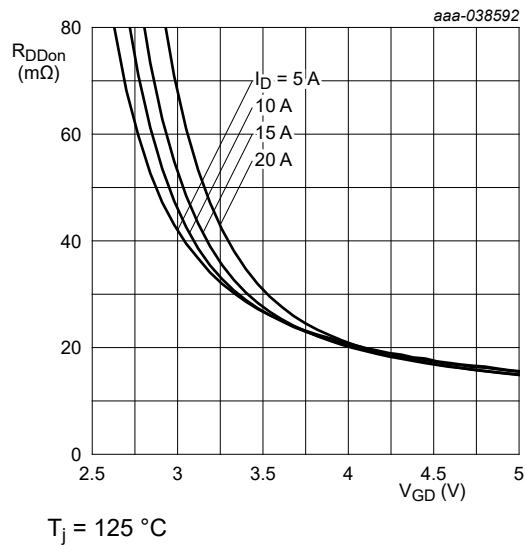


Fig. 12. Drain-drain on-state resistance as a function of gate-drain voltage; typical values

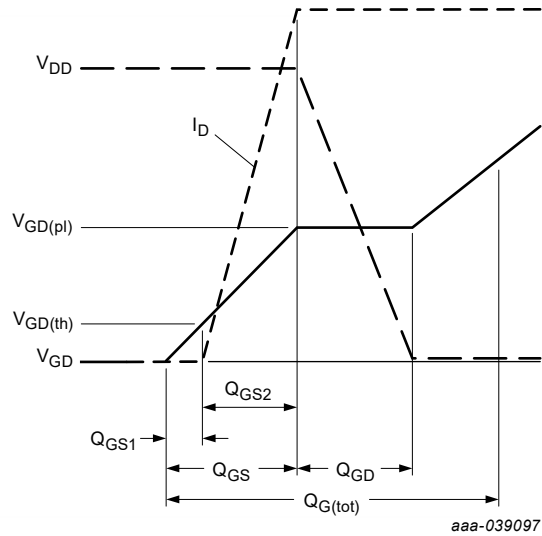


Fig. 13. Gate charge waveform definitions

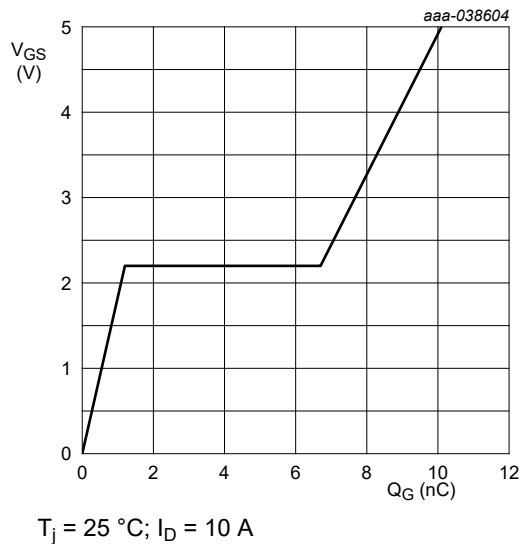


Fig. 14. Gate-source voltage as a function of gate charge; typical values

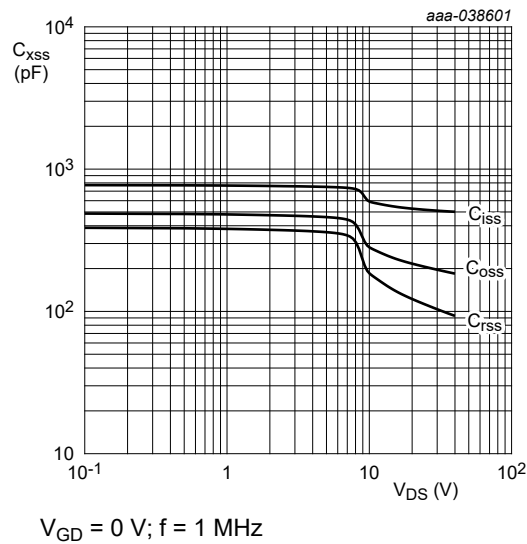


Fig. 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

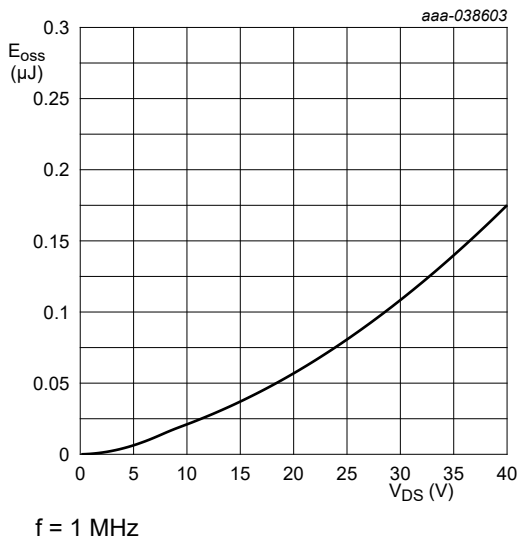


Fig. 16. C_{oss} stored energy as a function of drain-source voltage; typical values

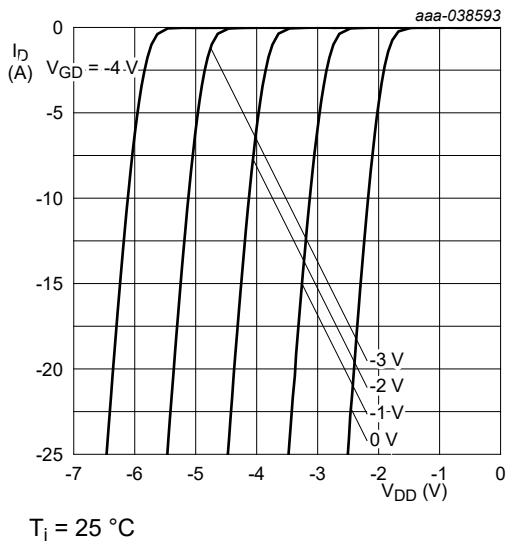


Fig. 17. Reverse drain current as a function of drain-drain voltage; typical values

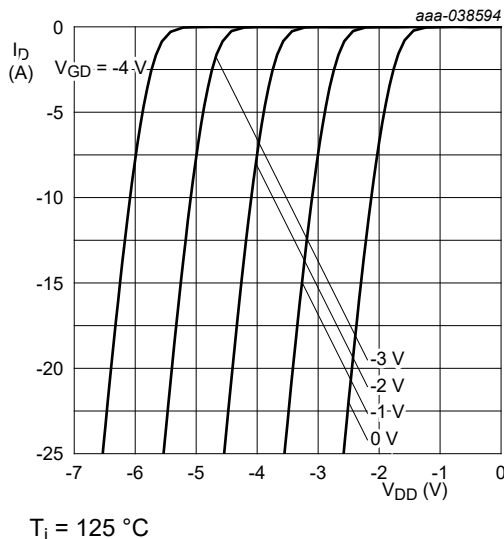


Fig. 18. Reverse drain current as a function of drain-drain voltage; typical values

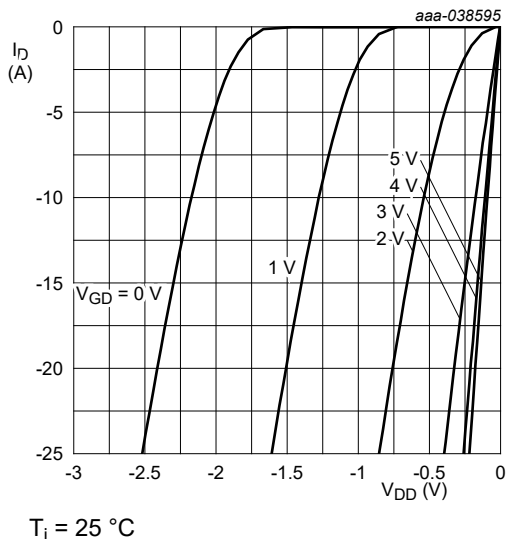
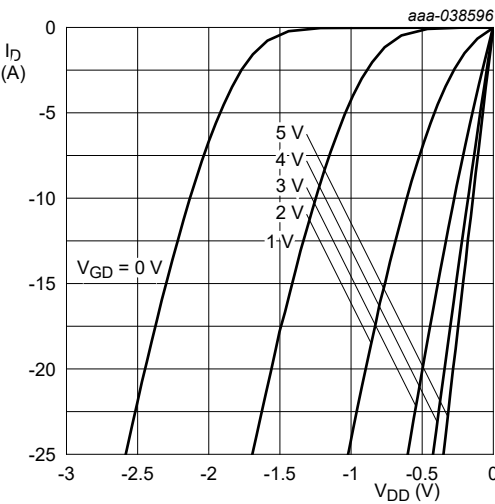


Fig. 19. Reverse drain current as a function of drain-drain voltage; typical values

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)



$T_j = 125\text{ }^{\circ}\text{C}$

Fig. 20. Reverse drain current as a function of drain-drain voltage; typical values

11. Package outline

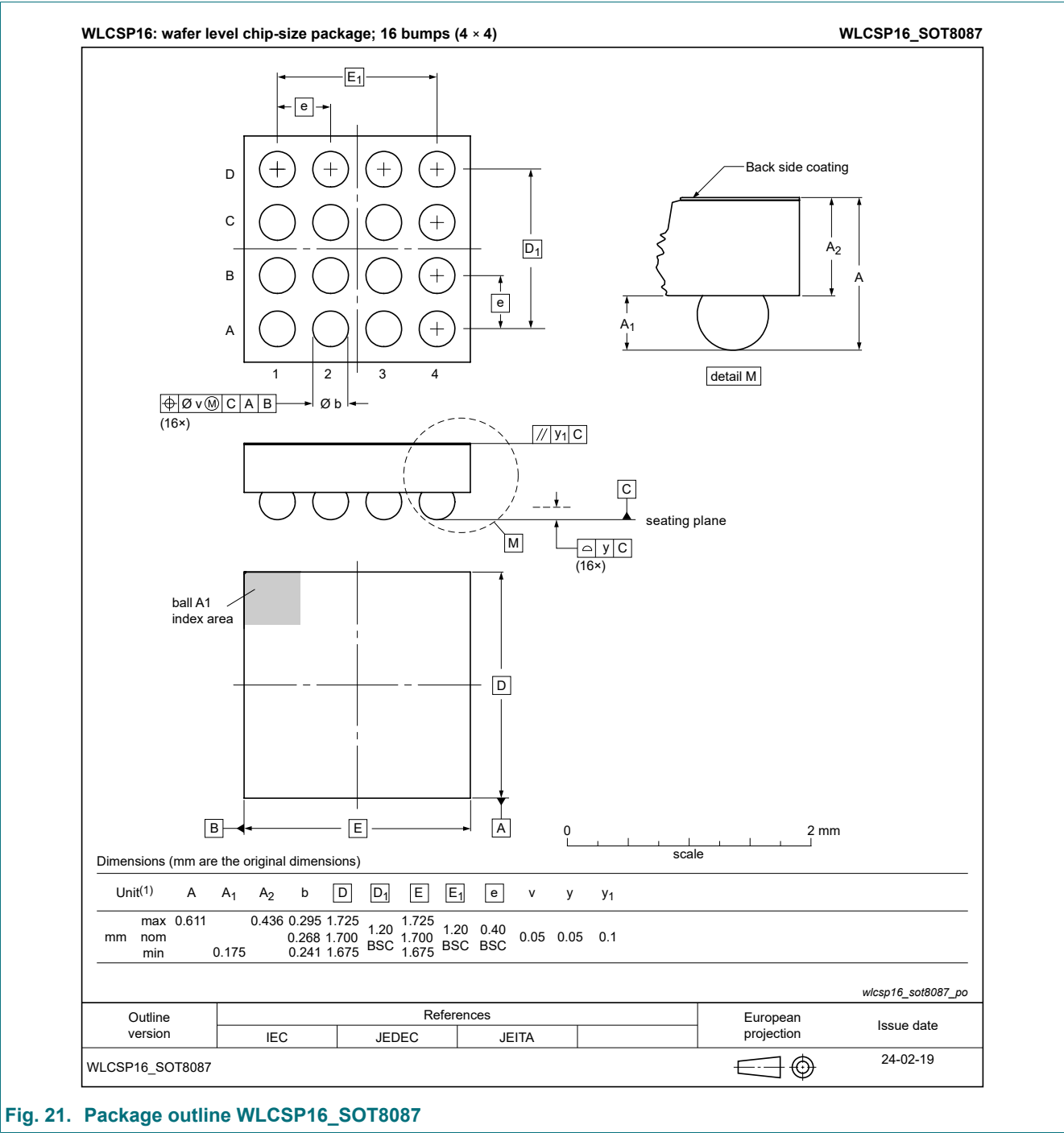
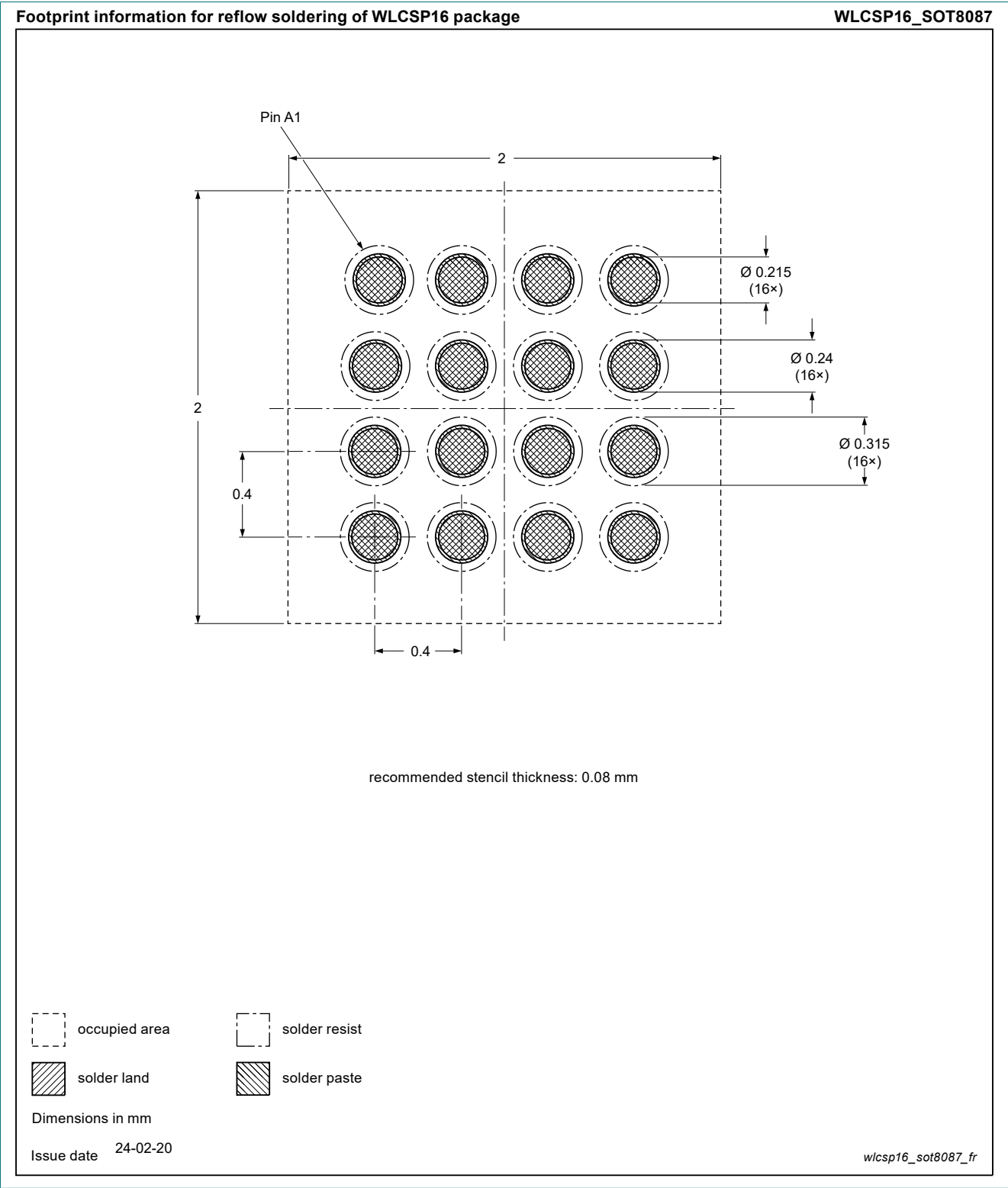


Fig. 21. Package outline WLCSP16_SOT8087

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

12. Soldering



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the internet at <https://www.nexperia.com>.

Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. Nexperia does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local Nexperia sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between Nexperia and its customer, unless Nexperia and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the Nexperia product is deemed to offer functions and qualities beyond those described in the Product data sheet.

Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, Nexperia does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. Nexperia takes no responsibility for the content in this document if provided by an information source outside of Nexperia.

In no event shall Nexperia be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, Nexperia's aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the Terms and conditions of commercial sale of Nexperia.

Right to make changes — Nexperia reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — Nexperia products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an Nexperia product can reasonably be expected to result in personal

injury, death or severe property or environmental damage. Nexperia and its suppliers accept no liability for inclusion and/or use of Nexperia products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. Nexperia makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using Nexperia products, and Nexperia accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the Nexperia product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

Nexperia does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using Nexperia products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). Nexperia does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — Nexperia products are sold subject to the general terms and conditions of commercial sale, as published at <http://www.nexperia.com/profile/terms>, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. Nexperia hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of Nexperia products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific Nexperia product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. Nexperia accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without Nexperia's warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond Nexperia's specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies Nexperia for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond Nexperia's standard warranty and Nexperia's product specifications.

Translations — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

40 V, 8.0 mOhm bi-directional Gallium Nitride (GaN) FET in a 1.7 mm x 1.7 mm Wafer Level Chip-Scale Package (WLCSP)

Contents

1. General description..... 1

2. Features and benefits..... 1

3. Applications..... 1

4. Quick reference data..... 1

5. Pinning information.....2

6. Ordering information.....2

7. Marking.....2

8. Limiting values..... 3

9. Thermal characteristics..... 4

10. Characteristics..... 5

11. Package outline..... 11

12. Soldering..... 12

13. Legal information.....13

© Nexperia B.V. 2025. All rights reserved

For more information, please visit: <http://www.nexperia.com>

For sales office addresses, please send an email to: salesaddresses@nexperia.com

Date of release: 31 January 2025